# Computer System Interoperability for Nanoscale Materials Testing

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#### Outline

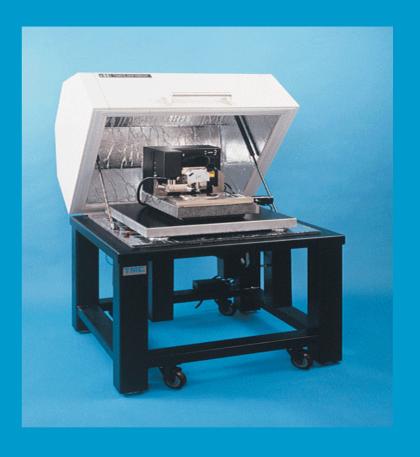
- Introduction
- Motivation Behind Project
- Purpose of Project
- Procedure
  - Translating a Computer algorithm
  - Scanning Tip Characterizer Samples
  - Scanning Nanoindenter Tips with an Atomic Force Microscope
  - Determining Actual Shape of Nanoindenter Tips
- Comparing Results
- Acknowledgements

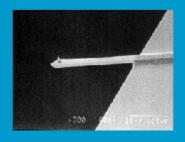


#### Introduction

- Basic things to know:
  - Atomic Force Microscope (AFM)
  - AFM Tip
  - Nanoindenter
  - Nanoindenter Tip

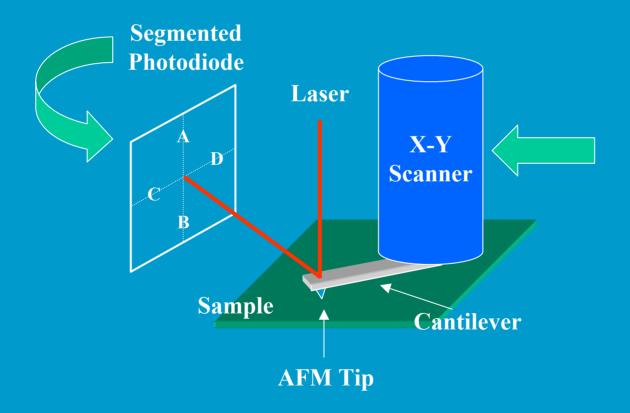








# Atomic Force Microscope





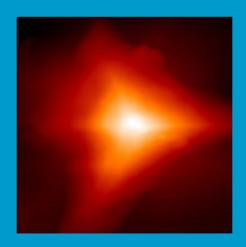
# Motivation and Purpose

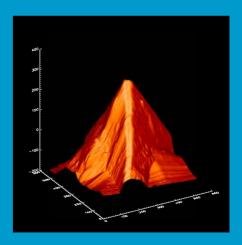
- Nanoindenter Tip shape needed for studies of mechanical properties of polymers
- Service Life Prediction
- Indentation of reference samples normally used to measure tip shape
- Determine Nanoindenter Tips shape by AFM imaging
- Transfer from UNIX to Windows



#### Translating a Computer Algorithm

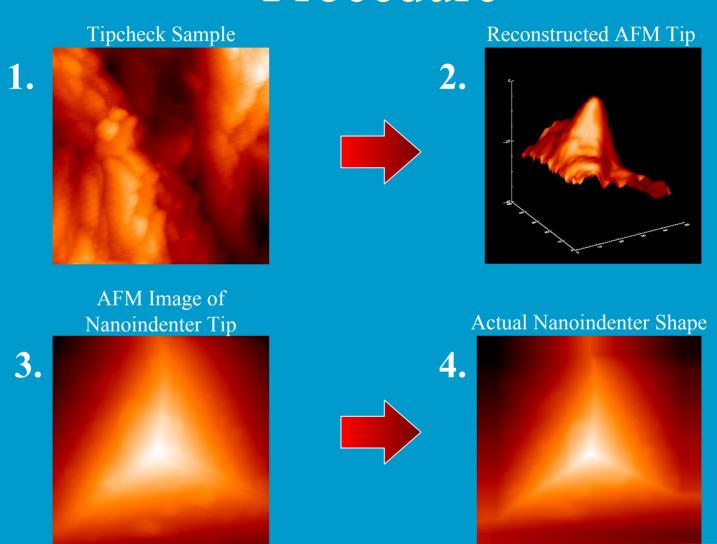
- UNIX to PC
- <u>Dynamic Link Library</u>a file that contains functions which can be called by other programs and DLLs to perform certain tasks and jobs.
- PV Wave
  - read\_nano4
  - fast\_tipest
  - erosion



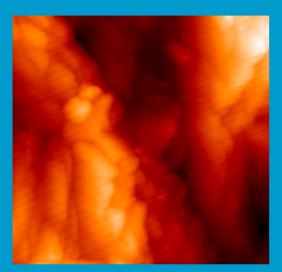




### Procedure

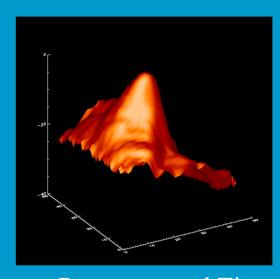


#### Reconstruction of the AFM Tip



Tip Characterizer Sample





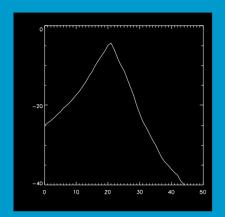
Reconstructed Tip

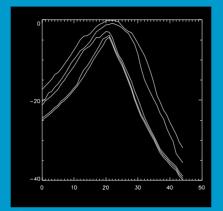
#### AFM image = nanoindenter tip shape + AFM tip geometry

wave> read\_nano4, "tiart4.f01",data, image
wave> tvscl, image
wave> rtip = fast\_tipest (image,45,45,thresh=2.4)
wave> surface, rtip

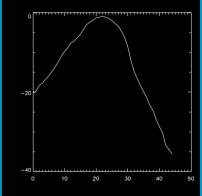


# Choosing a Threshold

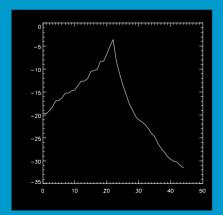


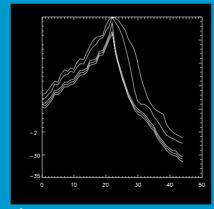




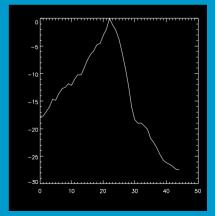


x-cross section







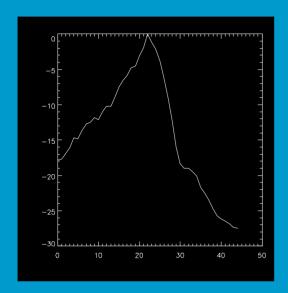


y-cross section

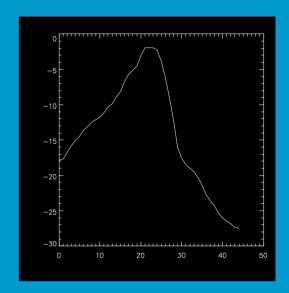


# Median Filtering

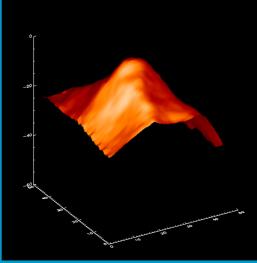
y-cross section





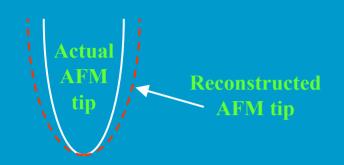


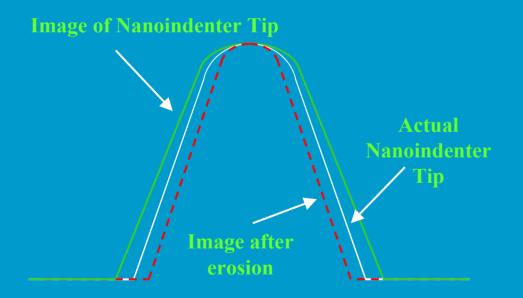
Reconstructed Tip

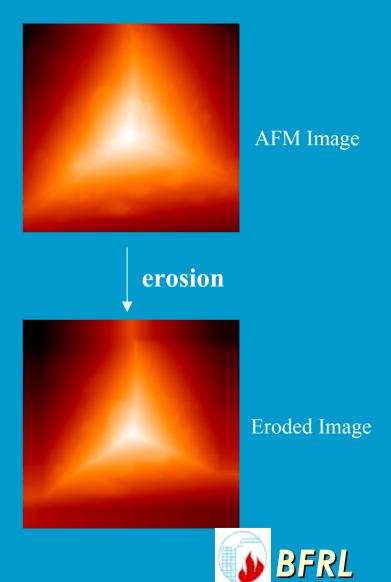




#### Erosion





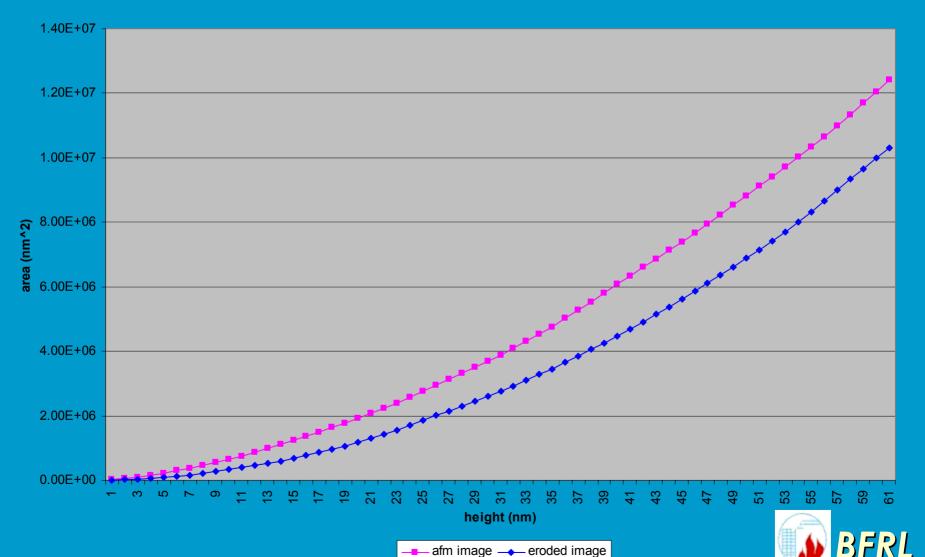




# Area Vs. Height



a\_vs\_h (berktip, tip1)



# Acknowledgements

- Mark VanLandingham
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- Stuart Dolls
- BFRL
- NIST

